BLF6G20LS-75

Power LDMOS transistor

Rev. 01 — 18 February 2008

Preliminary data sheet

1. Product profile

1.1 General description

 $75~\mathrm{W}$ LDMOS power transistor for base station applications at frequencies from 1800 MHz to 2000 MHz.

Table 1. Typical performance

RF performance at T_{case} = 25 °C in a common source class-AB production test circuit.

Mode of operation	f	V_{DS}	P _{L(AV)}	Gp	η _D	ACPR _{400k}	ACPR _{600k}	EVM _{rms}
	(MHz)	(V)	(W)	(dB)	(%)	(dBc)	(dBc)	(%)
CW	1930 to 1990	28	63	19	52	-	-	-
GSM EDGE	1930 to 1990	28	29.5	19	37.5	-61.5	-73	1.7

CAUTION



This device is sensitive to ElectroStatic Discharge (ESD). Therefore care should be taken during transport and handling.

1.2 Features

- Typical GSM EDGE performance at frequencies of 1930 MHz and 1990 MHz, a supply voltage of 28 V and an I_{Dq} of 550 mA:
 - Output power = 29.5 W (AV)
 - ◆ Gain = 19 dB
 - ◆ Efficiency = 37.5 %
 - ◆ ACPR_{400k} = −61.5 dBc
 - ◆ ACPR_{600k} = -73 dBc
 - ◆ EVM_{rms} = 1.7 %
- Easy power control
- Integrated ESD protection
- Excellent ruggedness
- High efficiency
- Excellent thermal stability
- Designed for broadband operation (1800 MHz to 2000 MHz)
- Internally matched for ease of use
- Compliant to Directive 2002/95/EC, regarding Restriction of Hazardous Substances (RoHS)



1.3 Applications

■ RF power amplifiers for GSM, GSM EDGE, W-CDMA and CDMA base stations and multi carrier applications in the 1800 MHz to 2000 MHz frequency range

2. Pinning information

Table 2. Pinning

	9		
Pin	Description	Simplified outline	Symbol
1	drain		
2	gate		ئے
3	source	[1]	2 — — 3 3 sym112
			*

^[1] Connected to flange.

3. Ordering information

Table 3. Ordering information

Type number	Package	9	
	Name	Description	Version
BLF6G20LS-75	-	earless flanged LDMOST ceramic package; 2 leads	SOT502B

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage		-	65	V
V_{GS}	gate-source voltage		-0.5	+13	V
I_D	drain current		-	18	Α
T_{stg}	storage temperature		-65	+150	°C
T_j	junction temperature		-	225	°C

5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Тур	Unit
$R_{\text{th(j-case)}}$	thermal resistance from junction to case	T_{case} = 80 °C; P_L = 29.5 W	0.75	K/W

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6. Characteristics

Table 6. Characteristics

 $T_i = 25 \,^{\circ}C$ unless otherwise specified.

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Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$V_{(BR)DSS}$	drain-source breakdown voltage	$V_{GS} = 0 \text{ V}; I_D = 0.5 \text{ mA}$	65	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$V_{DS} = 10 \text{ V}; I_{D} = 100 \text{ mA}$	1.4	2	2.4	V
V_{GSq}	gate-source quiescent voltage	$V_{DS} = 28 \text{ V}; I_{D} = 600 \text{ mA}$	1.6	2.1	2.6	V
I _{DSS}	drain leakage current	$V_{GS} = 0 \text{ V}; V_{DS} = 28 \text{ V}$	-	-	3	μΑ
I _{DSX}	drain cut-off current	$V_{GS} = V_{GS(th)} + 3.75 \text{ V};$ $V_{DS} = 10 \text{ V}$	14.9	18.5	-	Α
I_{GSS}	gate leakage current	$V_{GS} = 11 \text{ V}; V_{DS} = 0 \text{ V}$	-	-	300	nΑ
9 _{fs}	forward transconductance	$V_{DS} = 10 \text{ V}; I_D = 5 \text{ A}$	-	7	-	S
R _{DS(on)}	drain-source on-state resistance	$V_{GS} = V_{GS(th)} + 3.75 \text{ V};$ $I_D = 3.5 \text{ A}$	-	0.15	0.235	Ω
C _{rs}	feedback capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 28 \text{ V};$ f = 1 MHz	-	1.6	-	pF

7. Application information

Table 7. Application information

Mode of operation: GSM EDGE; f = 1930 MHz and 1990 MHz; RF performance at V_{DS} = 28 V; I_{Dq} = 550 mA; T_{case} = 25 °C; unless otherwise specified; in a class-AB production test circuit.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$P_{L(AV)}$	average output power		-	29.5	-	W
G_p	power gain	$P_{L(AV)} = 29.5 \text{ W}$	17.5	19	-	dB
IRL	input return loss	$P_{L(AV)} = 29.5 \text{ W}$	-	-10	-6.5	dB
η_{D}	drain efficiency	$P_{L(AV)} = 29.5 \text{ W}$	35.5	37.5	-	%
$ACPR_{400k}$	adjacent channel power ratio (400 kHz)	$P_{L(AV)} = 29.5 \text{ W}$	-	-61.5	-59.5	dBc
$ACPR_{600k}$	adjacent channel power ratio (600 kHz)	$P_{L(AV)} = 29.5 \text{ W}$	-	-73	-69.5	dBc
EVM_{rms}	RMS EDGE signal distortion error	$P_{L(AV)} = 29.5 \text{ W}$	-	1.7	2.7	%
EVM_M	peak EDGE signal distortion error	$P_{L(AV)} = 29.5 \text{ W}$	-	4.8	9	%

7.1 Ruggedness in class-AB operation

The BLF6G20LS-75 is capable of withstanding a load mismatch corresponding to VSWR = 10 : 1 through all phases under the following conditions: V_{DS} = 28 V; I_{Dq} = 550 mA; P_{L} = 75 W (CW); f = 1990 MHz.

7.2 One-tone CW

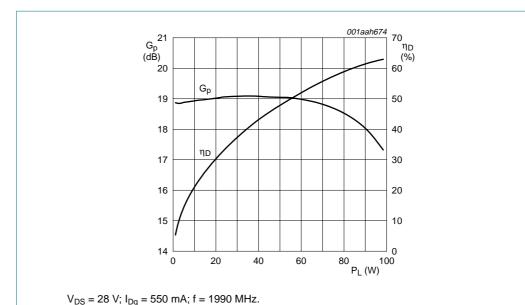


Fig 1. One-tone CW power gain and drain efficiency as functions of load power; typical values

7.3 Two-tone CW

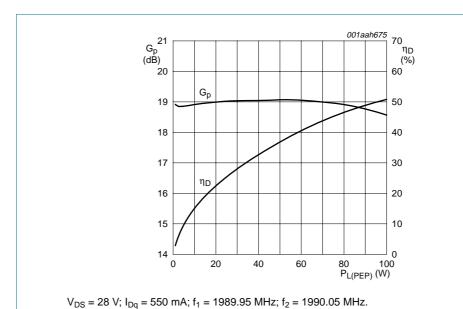
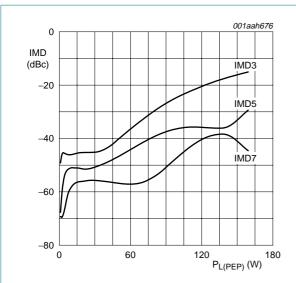
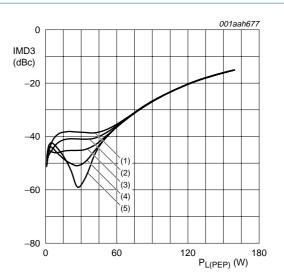


Fig 2. Two-tone CW power gain and drain efficiency as functions of peak envelope load power; typical values



 V_{DS} = 28 V; I_{Dq} = 550 mA; f_1 = 1989.95 MHz; f_2 = 1900.05 MHz.

Fig 3. Two-tone CW intermodulation distortion as function of peak envelope load power; typical values



 $V_{DS} = 28 \text{ V}$; $f_1 = 1989.95 \text{ MHz}$; $f_2 = 1900.05 \text{ MHz}$.

- (1) 450 MHz
- (2) 500 MHz
- (3) 550 MHz
- (4) 600 MHz
- (5) 650 MHz

Fig 4. Third order intermodulation distortion as a function of peak envelope load power; typical values

7.4 GSM-EDGE

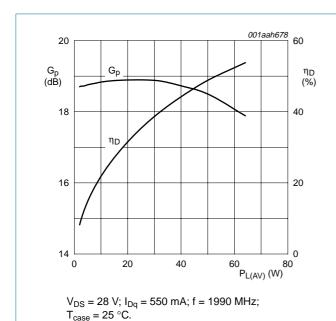
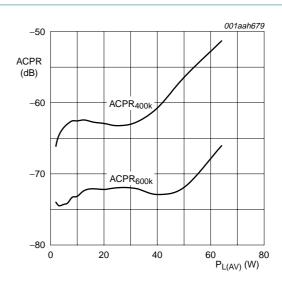
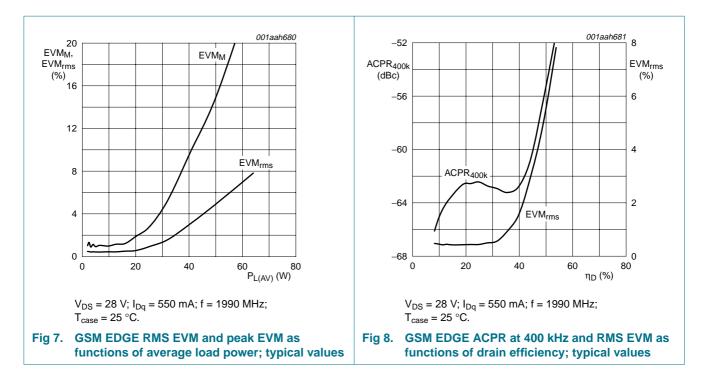


Fig 5. GSM-EDGE power gain and drain efficiency as functions of average load power; typical values

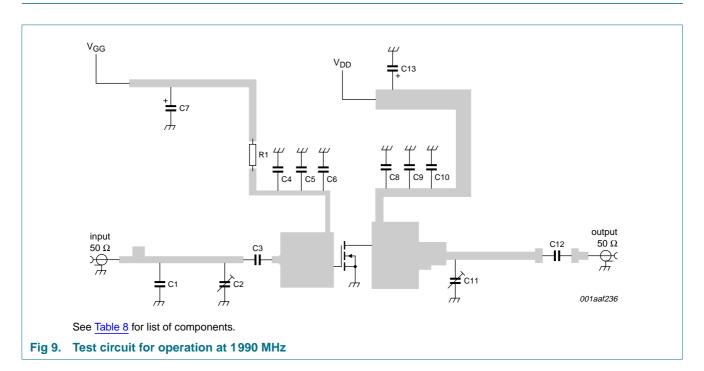


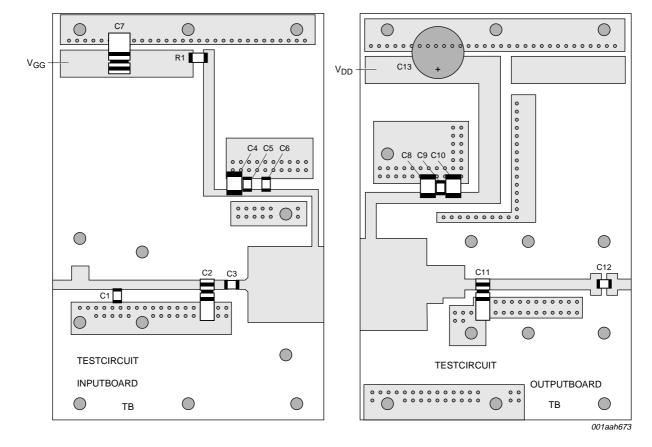
 V_{DS} = 28 V; I_{Dq} = 550 mA; f = 1990 MHz; T_{case} = 25 °C.

Fig 6. GSM-EDGE ACPR at 400 kHz and at 600 kHz as functions of average load power; typical values



8. Test information





The striplines are on a double copper-clad Taconic RF35 Printed-Circuit Board (PCB) with ϵ_{r} = 3.5 and thickness = 0.76 mm.

See Table 8 for list of components.

Fig 10. Component layout for 1990 MHz test circuit

Table 8. List of components (see Figure 9 and Figure 10)

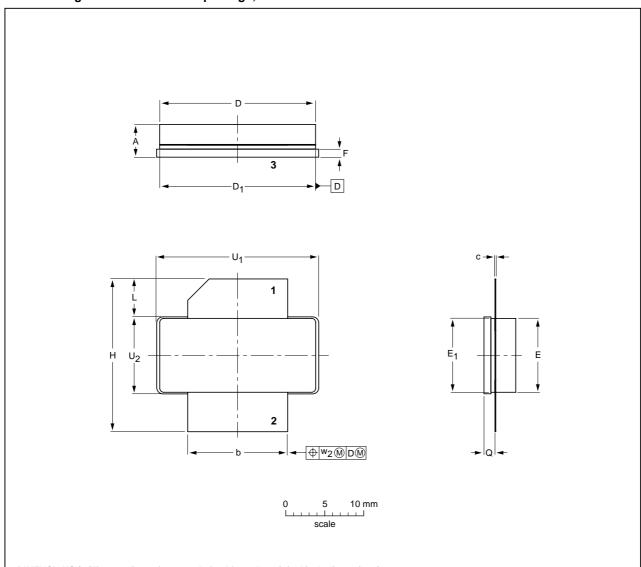
Component	Description	Value	Remarks
C1	multilayer ceramic chip capacitor	1 pF [1
C2, C11	gigahertz trimmer	0.6 pF to 4.5 pF	Temex AT SM270 or equivalent
C3, C6, C9	multilayer ceramic chip capacitor	12 pF	1
C4, C8, C10	multilayer ceramic chip capacitor	10 μF; 50 V	TDK C5750X7R1H106M or equivalent
C5	multilayer ceramic chip capacitor	1.5 μF; 50 V	TDK C3225X7R1H155M or equivalent
C7	tantalum capacitor	10 μF; 50 V	Kemet T491 series or equivalent
C12	multilayer ceramic chip capacitor	12 pF	1
C13	electrolytic capacitor	220 μF; 50 V	
R1	Philips chip resistor	5.6 Ω	SMD 1206

^[1] American Technical Ceramics type 100B or capacitor of same quality.

9. Package outline

Earless flanged LDMOST ceramic package; 2 leads

SOT502B



DIMENSIONS (millimetre dimensions are derived from the original inch dimensions)

UNIT	A	b	С	D	D ₁	E	E ₁	F	Н	L	Q	U ₁	U ₂	w ₂
mm	4.72 3.43	12.83 12.57	0.15 0.08	20.02 19.61		9.50 9.30	9.53 9.25	1.14 0.89	19.94 18.92	5.33 4.32	1.70 1.45	20.70 20.45	9.91 9.65	0.25
inches	0.186 0.135	0.505 0.495		0.788 0.772	0.786 0.774	0.374 0.366	0.375 0.364	0.045 0.035	0.785 0.745	0.210 0.170	0.067 0.057	0.815 0.805	0.390 0.380	0.010

OUTLINE		REFER	ENCES	EUROPEAN	ICCUE DATE	
VERSION	IEC	JEDEC	JEITA	PROJECTION	ISSUE DATE	
SOT502B					03-01-10- 07-05-09	

Fig 11. Package outline SOT502B

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10. Abbreviations

Table 9. Abbreviations

Acronym	Description
CDMA	Code Division Multiple Access
CW	Continuous Wave
EDGE	Enhanced Data rates for GSM Evolution
EVM	Error Vector Magnitude
GSM	Global System for Mobile communications
LDMOS	Laterally Diffused Metal Oxide Semiconductor
LDMOST	Laterally Diffused Metal-Oxide Semiconductor Transistor
RF	Radio Frequency
RMS	Root Mean Square
VSWR	Voltage Standing Wave Ratio
W-CDMA	Wideband Code Division Multiple Access

11. Revision history

Table 10. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
BLF6G20LS-75_1	20080218	Preliminary data sheet	-	-

12. Legal information

12.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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- [2] The term 'short data sheet' is explained in section "Definitions"
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